


IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**Applicant(s):** Tze-chiang Chen, et al.**Examiner:** C.Q. Nguyen**Serial No:** 10/700,085**Art Unit:** 2811**Filed:** November 3, 2003**Docket:** YOR920030586US1 (17201)**For:** METHOD FOR FABRICATING
SiGe-ON-INSULATOR (SGOI) AND
Ge-ON-INSULATOR (GOI) SUBSTRATES**Dated:** August 31, 2004**RECEIVED
CENTRAL FAX CENTER****AUG 31 2004**Commissioner for Patents
United States Patent and Trademark Office
Alexandria, VA 22313-1450**RESPONSE UNDER 37 C.F.R. §§1.111 AND 1.143****Sir:**

In response to the Office Action dated August 20, 2004, applicants provisionally elect, without traverse, the subject matter of Group I, i.e., Claims 1-36, for continued prosecution in the above-identified patent application.

CERTIFICATION OF FACSIMILE TRANSMISSION

I hereby certify that this paper is being facsimile transmitted to the Patent and Trademark Office on the date shown below.

Dated: August 31, 2004
Leslie S. Szivos, Ph.D.**BEST AVAILABLE COPY**

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